CIL EMU CRITICAL ITEMS LIST			5/30/2002 SUPERSEDES 12/31/2001		Page 1 Date: 4/24/2002
NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE	
		350FM01			
DCM ELECTRONICS, ITEM 350 (PIVOTED, PLANAR)	3/2RB	Loss of primary SSER power.  Semiconductor or solder joint failure, broken connection, output printed circuit trace shorts to ground.	END ITEM: Loss of power on primary SSER power line.  GFE INTERFACE: Loss of primary SSER power. SSER will continue to operate from secondary power line.  MISSION: None for single failure. Terminate EVA for an additional loss of operationally redundant secondary EVC power line.  CREW/VEHICLE: None.  TIME TO EFFECT /ACTIONS: Seconds.  TIME AVAILABLE: Days.  TIME REQUIRED: Days.  REDUNDANCY SCREENS:	A. Design - Semiconductor failure is minimized through the use of his components. Established reliability capacitors (level S) R) are used and are qualified to the requirements of thei and thermal shocked per condition B of MIL-STD-202 Method and diodes are qualified to the requirements of MIL-S-199 in of JANTXV level parts per the applicable methods, 1038 STD-750. The electronic components are operating within requirements of SVHS 7804. The printed circuit boards are 13949 Type GI and manufactured per SN-P-0006. Parts mour per MSFC-STD-136 and NHB5300.4 (3A-1). The board assembl the DCM case to provide a thermal transfer path between t the case to direct heat away from the electronic componer assemblies are also conformal coated per MIL-A-46146 (Dow environmental protection.  All wiring used in the DCM is M22759/11 (teflon insulated NHB5300.4 (3A-1) and wire crimping is per SVHS 4909 (base All wires are strain relieved.  Electrical connectors are environmentally sealed to preve contamination and humidity.  B. Test - In-process: The DCM electronics assembly is tested during initial but assembly level, after the PC boards have been interwired, the boards and wiring, and after installation of the fror consist of continuity through the switches and wiring, vc check of all current limiters, and full operation of the tests insure proper operation of all electronic component PDA:  Vibration testing per SEMU-60-015 followed by continuity testing verifies the integrity of the solder joints and c DCM. The random vibration level for this test is 6.6 grms minute per axis for each of the three orthogonal axes.  (JSC Spec SP-T-0023)  Thermal Vacuum testing followed by full functional electr 60-015 also verifies the health of the solder joints as w acceptability of the components. The DCM is placed in a 10-3 torr. The DCM case temperature is cycled 3 times fr At the end of the third cycle, the temperature is held be For a minimum of four hours. The DCM display must reme	and resistors (level r respective MIL specs 107. The transistors 00 and receive the burn-, 1039 and 1040, of MIL-the power derating polyimide per MIL-P-ting and soldering is ies are hard mounted to he board heatsinks and ts. The board Corning RTV 3140) for 0. Soldering is per d on MSC-SPEC-Q-1A).  It damage due to 1d-up: at the board after installation of t cover. These tests ltage checks, functional DCM electronics. The s.  and full functional rimp connections in the for a duration of 1 ical testing per SEMU-ell as the vacuum chamber at 1 x om 70 to 130 degree F. tweem 130 & 135 degrees

F for a minimum of four hours. The DCM display must remain on throughout the test. This verifies proper transfer of heat from the electronics to the DCM case to prevent overheating of components.

Certification Test -Certified for a useful life of 25 years (Ref. EMUM1-0332).

C. Inspection -

A-PASS

B-FAIL

C-PASS

100% inspection of all soldering (PC boards and wiring) by Hamilton Standard QA

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FAILURE EFFECT RATIONALE FOR ACCEPTANCE

350FM01

CRIT

CAUSES

and DCAS QA per quidelines in NHB-5300-4.

All board assemblies are inspected for damage and contamination. All wiring is inspected for damage, nicks in the insulation, wear, and strain relief.

The DCM is internally inspected after installation of the circuit boards and wiring to insure no damage has occurred during assembly.

- D. Failure History None.
- E. Ground Turnaround None for single failure.
- F. Operational Use -

Crew Response
Pre-EVA/EVA: No response, single failure undetectable by crew or ground.
Special Training

No training specifically covers this failure mode.

Operational Considerations

For single failure, no constraints.

Flight rules require that EVA be terminated if two-way communication between each EVA crewmember and orbiter, either direct or through relay is unavailable.

## EXTRAVEHICULAR MOBILITY UNIT SYSTEMS SAFETY REVIEW PANEL REVIEW

FOR THE

I-350 DCM ELECTRONIC ASSEMBLY

CRITICAL ITEM LIST (CIL)

EMU CONTRACT NO. NAS 9-97150

Prepared by:

AS - Project Engineering

Approved by:

District Control

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NASAT Crew

ASA Program Manager